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10/710,947

FIS920040092US2



| <b>IN THE UNITED STATES PATENT AND TRADEMARK OFFICE</b>  |   |
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| In re application of: <b>Michael P. Chudzik, et al.</b>  | Date: <b>September 15, 2008</b>   |
| Serial Number: <b>10/710,947</b>   | Examiner: <b>Amy He</b>   |
| Filed: <b>8/13/2004</b>  | Group Art Unit: <b>2831</b><br>Confirmation No. : <b>4946</b>                                 |
| Title: <b>Methods for the determination of film continuity and growth modes in thin dielectric films</b> | IBM Corporation<br>D/18G, B/321, Zip 482<br>2070 Route 52<br>Hopewell Junction, NY 12533-6531 |

**AMENDMENT UNDER 37C.F.R. § 312 AFTER ALLOWANCE**

Commissioner of Patents and Trademarks  
P. O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Responsive to the Notice of Allowance and Fees due dated June 26, 2008, the following Amendment is being submitted.

Kindly amend the Specification as follows: